

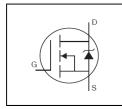
## **AUTOMOTIVE GRADE**

# AUIRF1010Z AUIRF1010ZS AUIRF1010ZL

HEXEET® POWER MOSEET

#### Features

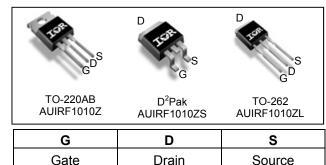
- Advanced Process Technology
- Ultra Low On-Resistance
- 175°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Timax
- · Lead-Free, RoHS Compliant
- Automotive Qualified \*



	ET FOWEI MOSFET
V <sub>DSS</sub>	55V
R <sub>DS(on)</sub> max.	7.5mΩ
D (Silicon Limited)	94A
D (Package Limited)	75A

## **Description**

Specifically designed for Automotive applications, this HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 175°C junction operating temperature, fast switching speed and improved repetitive avalanche rating. These features combine to make this design an extremely efficient and reliable device for use in Automotive applications and a wide variety of other applications.



Base west sumber   Backeye Time		Standard Pack	(	Ouderable Best Neurober
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRF1010Z	TO-220	Tube	50	AUIRF1010Z
AUIRF1010ZL	TO-262	Tube	50	AUIRF1010ZL
AUIRF1010ZS	D²-Pak	Tube	50	AUIRF1010ZS
AUIRF 10 1025	D-Pak	Tape and Reel Left	800	AUIRF1010ZSTRL

### **Absolute Maximum Ratings**

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	94	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	66	1
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Package Limited)	75	A
I <sub>DM</sub>	Pulsed Drain Current ①	360	
P <sub>D</sub> @T <sub>C</sub> = 25°C	Maximum Power Dissipation	140	W
	Linear Derating Factor	0.90	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	V
E <sub>AS</sub>	Single Pulse Avalanche Energy (Thermally Limited) ②	130	ma I
E <sub>AS</sub> (tested)	Single Pulse Avalanche Energy Tested Value ®	180	mJ
I <sub>AR</sub>	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ®		mJ
TJ	Operating Junction and	-55 to + 175	
$T_{STG}$	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	
	Mounting torque, 6-32 or M3 screw⑦	10 lbf•in (1.1N•m)	

#### Thermal Resistance

Symbol	Parameter	Тур.	Max.	Units
Rejc	Junction-to-Case 9		1.11	
$R_{ heta CS}$	Case-to-Sink, Flat, Greased Surface ⑦	0.50		°C/\\
$R_{\thetaJA}$	Junction-to-Ambient ⑦		62	°C/W
$R_{ hetaJA}$	Junction-to-Ambient ( PCB Mount, steady state) ®		40	

HEXFET® is a registered trademark of Infineon.

<sup>\*</sup>Qualification standards can be found at www.infineon.com



## Static @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.049		V/°C	Reference to 25°C, I <sub>D</sub> = 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance		5.8	7.5	mΩ	V <sub>GS</sub> = 10V, I <sub>D</sub> = 75A ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
gfs	Forward Trans conductance	33			S	$V_{DS} = 25V, I_{D} = 75A$
	Drain-to-Source Leakage Current			20		$V_{DS} = 55 \text{ V}, V_{GS} = 0 \text{ V}$
I <sub>DSS</sub>	Drain-to-Source Leakage Current			250	μA	$V_{DS} = 55V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			200	- Δ	V <sub>GS</sub> = 20V
llooo -	Gate-to-Source Reverse Leakage			-200	nA	$V_{GS} = -20V$

## Dynamic Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

-	•		-	_		
$Q_g$	Total Gate Charge		63	95		I <sub>D</sub> = 75A
$Q_{gs}$	Gate-to-Source Charge		19		nC	$V_{DS} = 44V$
$Q_{gd}$	Gate-to-Drain Charge		24			V <sub>GS</sub> = 10V3
$t_{d(on)}$	Turn-On Delay Time	I	18			$V_{DD} = 28V$
t <sub>r</sub>	Rise Time		150		no	I <sub>D</sub> = 75A
$t_{d(off)}$	Turn-Off Delay Time	T	36		ns	$R_G = 6.8\Omega$
t <sub>f</sub>	Fall Time		92			V <sub>GS</sub> = 10V ③
$L_D$	Internal Drain Inductance		4.5		nH	Between lead, 6mm (0.25in.)
Ls	Internal Source Inductance		7.5		Ш	from package and center of die contact
C <sub>iss</sub>	Input Capacitance		2840			$V_{GS} = 0V$
Coss	Output Capacitance		420			$V_{DS} = 25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		250		٦٦	f = 1.0MHz, See Fig. 5
C <sub>oss</sub>	Output Capacitance	I	1630		pF	$V_{GS} = 0V, V_{DS} = 1.0V f = 1.0MHz$
Coss	Output Capacitance		360			$V_{GS} = 0V$ , $V_{DS} = 44V$ $f = 1.0MHz$
Coss eff.	Effective Output Capacitance		560			$V_{GS}$ = 0V, $V_{DS}$ = 0V to 44V $\textcircled{4}$

## **Diode Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)			75	_	MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			360		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 75A, V_{GS} = 0V$ ③
t <sub>rr</sub>	Reverse Recovery Time		22	33	ns	$T_J = 25^{\circ}C$ , $I_F = 75A$ , $V_{DD} = 25V$
$Q_{rr}$	Reverse Recovery Charge		15	23	nC	di/dt = 100A/µs ③
t <sub>on</sub>	Forward Turn-On Time	Intrinsio	Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )			

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- ② Limited by  $T_{Jmax}$ , starting  $T_J = 25$ °C, L = 0.05mH,  $R_G = 25\Omega$ ,  $I_{AS} = 75$ A,  $V_{GS} = 10$ V. Part not recommended for use above this value.
- $\oplus$  C<sub>oss</sub> eff. is a fixed capacitance that gives the same charging time as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- © Limited by T<sub>Jmax</sub>, see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- $\odot$  This value determined from sample failure population, starting T<sub>J</sub> = 25°C, L = 0.05mH, R<sub>G</sub> = 25 $\Omega$ , I<sub>AS</sub> = 75A, V<sub>GS</sub> =10V.
- This is only applied to TO-220AB package.
- When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994



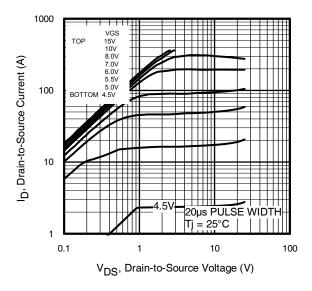


Fig. 1 Typical Output Characteristics

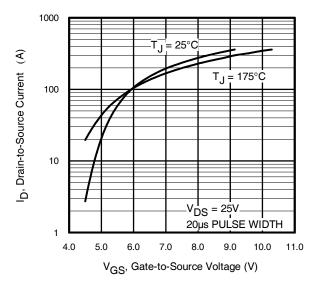


Fig. 3 Typical Transfer Characteristics

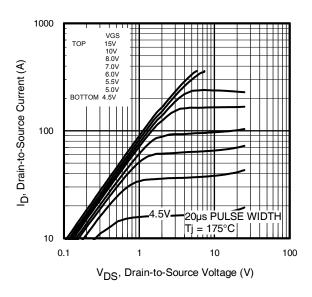
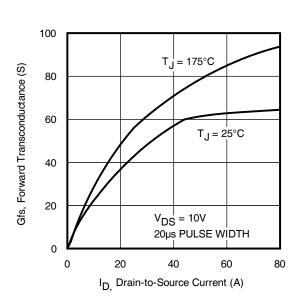
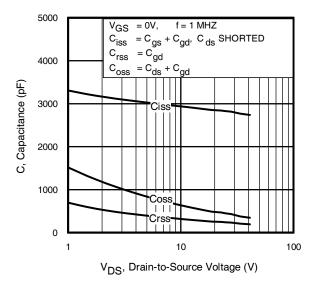


Fig. 2 Typical Output Characteristics

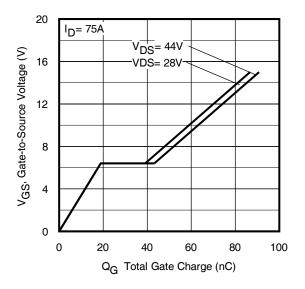


**Fig. 4** Typical Forward Trans conductance vs. Drain Current





**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



**Fig 6.** Typical Gate Charge vs. Gate-to-Source Voltage

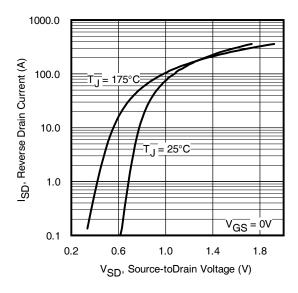


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

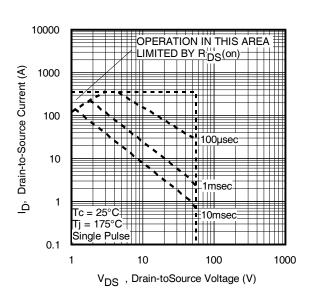
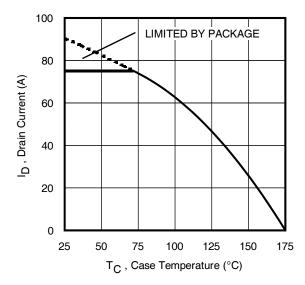


Fig 8. Maximum Safe Operating Area





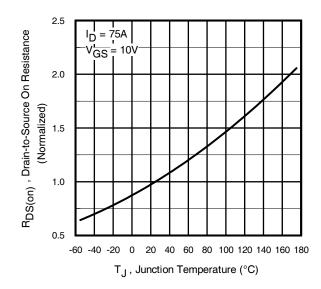


Fig 9. Maximum Drain Current vs. Case Temperature

**Fig 10.** Normalized On-Resistance vs. Temperature

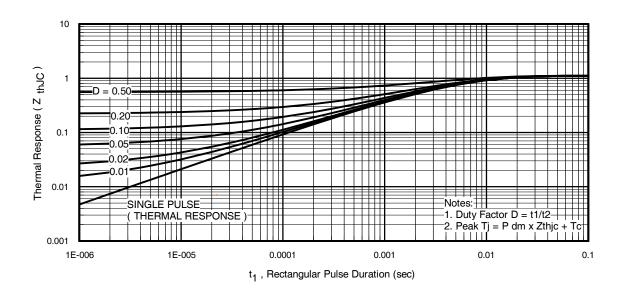


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



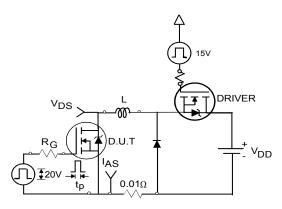


Fig 12a. Unclamped Inductive Test Circuit

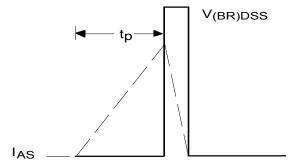


Fig 12b. Unclamped Inductive Waveforms

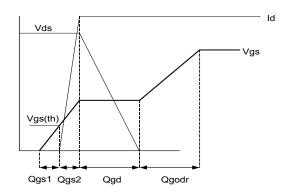


Fig 13a. Gate Charge Waveform

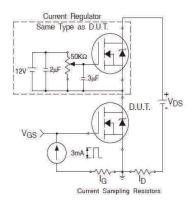
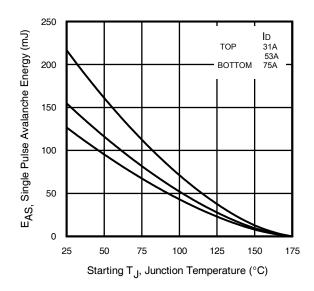


Fig 13b. Gate Charge Test Circuit



**Fig 12c.** Maximum Avalanche Energy vs. Drain Current

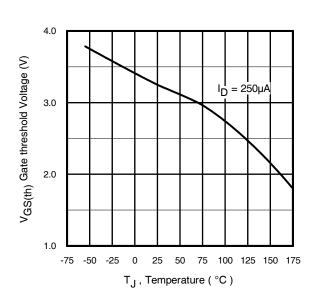


Fig 14. Threshold Voltage vs. Temperature



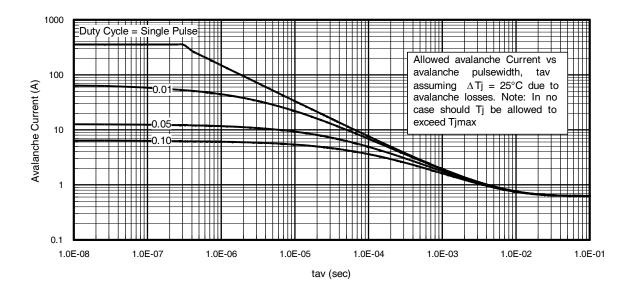
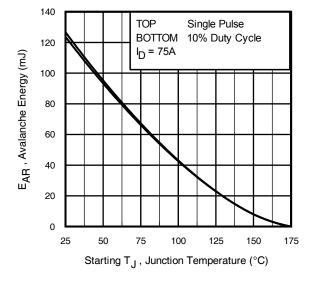


Fig 15. Typical Avalanche Current vs. Pulse width



**Fig 16.** Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T<sub>jmax</sub>. This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. Iav = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{jmax}$  (assumed as 25°C in Figure 15, 16).

tav = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \; (ave)} &= 1/2 \; (\; 1.3 \cdot BV \cdot I_{av}) = \Delta T / \; Z_{thJC} \\ I_{av} &= 2\Delta T / \; [1.3 \cdot BV \cdot Z_{th}] \\ E_{AS \; (AR)} &= P_{D \; (ave)} \cdot t_{av} \end{split}$$



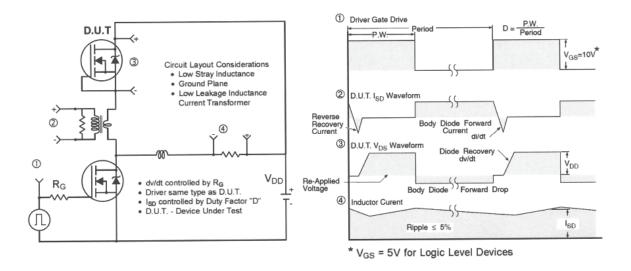


Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

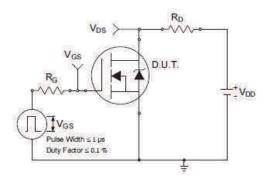


Fig 18a. Switching Time Test Circuit

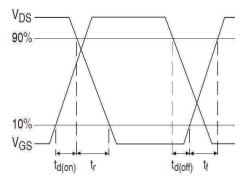
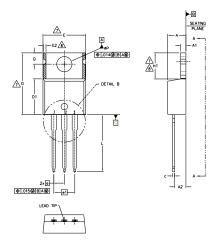
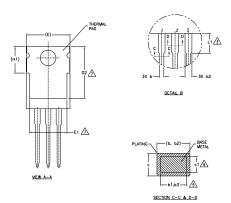


Fig 18b. Switching Time Waveforms



## TO-220AB Package Outline (Dimensions are shown in millimeters (inches))





#### NOTES:

- DIMENSIONING AND TOLERANCING AS PER ASME Y14.5 M- 1994.

- DIMENSIONING AND TOLERANGING AS PER ASME 114.5 M = 1994.

  DIMENSIONS ARE SHOWN IN INCHES [MILLIMETERS].

  LEAD DIMENSION AND FINISH UNCONTROLLED IN L1.

  DIMENSION D, D1 & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH

  SHALL NOT EXCEED .005" (0.127) PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.

DIMENSION 61, 63 & c1 APPLY TO BASE METAL ONLY.

- CONTROLLING DIMENSION: INCHES.
- THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSIONS E,H1,D2 & E1
- DIMENSION E2 X H1 DEFINE A ZONE WHERE STAMPING AND SINGULATION IRREGULARITIES ARE ALLOWED.
- OUTLINE CONFORMS TO JEDEC TO-220, EXCEPT A2 (max.) AND D2 (min.) WHERE DIMENSIONS ARE DERIVED FROM THE ACTUAL PACKAGE OUTLINE.

SYMBOL	MILLIM	ETERS	INC	HES	
	MIN.	MAX.	MIN.	MAX.	NOTES
Α	3.56	4.83	.140	.190	
A1	1.14	1.40	.045	.055	
A2	2.03	2.92	.080	.115	
b	0.38	1.01	.015	.040	
b1	0.38	0.97	.015	.038	5
b2	1,14	1.78	.045	.070	
b3	1,14	1.73	.045	.068	5
С	0.36	0.61	.014	.024	
c1	0.36	0.56	.014	.022	5
D	14.22	16.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	11.68	12.88	.460	.507	7
E	9.65	10.67	.380	.420	4,7
E1	6.86	8.89	.270	.350	7
E2	-	0.76	-	.030	8
e	2.54 5.08	BSC	.100 .200	BSC	
e1	5.08	BSC	.200	BSC	
H1	5.84	6.86	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	3.56	4.06	.140	.160	3
ØΡ	3.54	4.08	.139	.161	
Q	2.54	3.42	.100	.135	

#### LEAD ASSIGNMENTS

#### HEXFET

- 1.- GATE 2.- DRAIN 3.- SOURCE

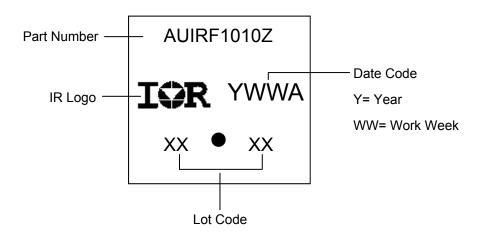
#### IGBTs, CoPACK

1.- GATE 2.- COLLECTOR 3.- EMITTER

#### DIODES

- 1.- ANODE 2.- CATHODE 3.- ANODE

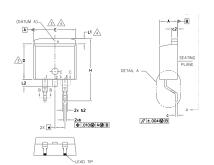
## **TO-220AB Part Marking Information**

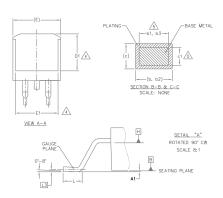


TO-220AB package is not recommended for Surface Mount Application.



# D<sup>2</sup>Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S		DIMENSIONS				
M B	MILLIM	ETERS	INC	HES	O T E S	
0 L	MIN.	MAX.	MIN.	MAX.	S	
А	4.06	4.83	.160	.190		
A1	0.00	0.254	.000	.010		
ь	0.51	0.99	.020	.039		
ь1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
ь3	1.14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	_	.270	_	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	_	.245	_	4	
е	2.54	BSC	.100	BSC		
Н	14.61	15.88	.575	.625		
L	1.78	2.79	.070	.110		
L1	_	1.68	_	.066	4	
L2	_	1.78	_	.070		
L3	0.25	BSC	.010	BSC		

#### LEAD ASSIGNMENTS

#### DIODES

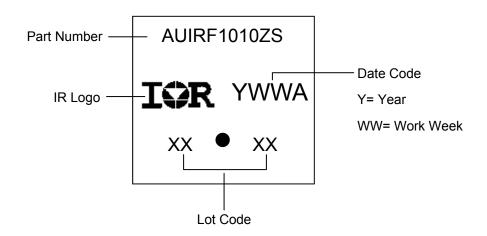
1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

## HEXFET

IGBTs, CoPACK

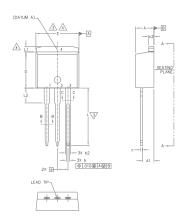
1.- GATE 2, 4.- DRAIN 3.- SOURCE 2, 4.- COLLECTOR 3.- EMITTER

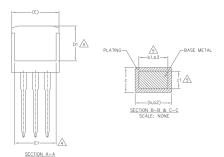
# D<sup>2</sup>Pak (TO-263AB) Part Marking Information





## TO-262 Package Outline (Dimensions are shown in millimeters (inches)





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- 3\DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. CONTROLLING DIMENSION: INCH.
- 7.- OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

#### LEAD ASSIGNMENTS

#### IGBTs, CoPACK

- 1.- GATE 2.- COLLECTOR 3.- EMITTER 4.- COLLECTOR

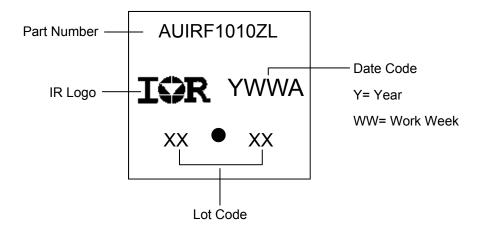
#### HEXFET DIODES

- 1.- GATE 2.- DRAIN 3.- SOURCE
- 1.- ANODE (TWO DIE) / OPEN (ONE DIE)
  2, 4.- CATHODE
  3.- ANODE

4.	- D	RAI

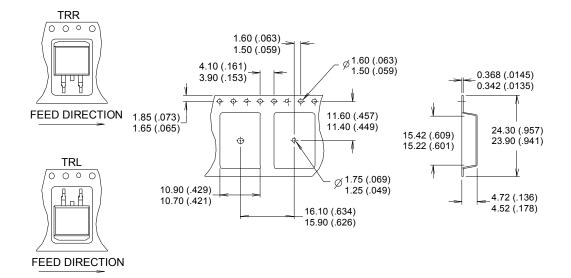
S Y M		DIMENSIONS				
В	MILLIM	ETERS	INC	INCHES		
0 L	MIN.	MAX.	MIN.	MAX.	O T E S	
А	4.06	4.83	.160	.190		
A1	2.03	3.02	.080	.119		
b	0.51	0.99	.020	.039		
ь1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
ь3	1.14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	-	.270	_	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	-	.245		4	
е	2.54	BSC	.100	BSC		
L	13.46	14.10	.530	.555		
L1	_	1.65	-	.065	4	
L2	3.56	3.71	.140	.146		

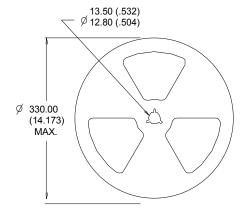
## **TO-262 Part Marking Information**





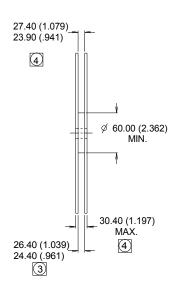
# D<sup>2</sup>Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







- COMFORMS TO EIA-418.
- CONTROLLING DIMENSION: MILLIMETER.
- 3
- DIMENSION MEASURED @ HUB.
  INCLUDES FLANGE DISTORTION @ OUTER EDGE.





#### **Qualification Information**

		Automotive				
			(per AEC-Q101)			
Qualification Level			is part number(s) passed Automotive qualification. Infineon's consumer qualification level is granted by extension of the highered.			
Moisture Sensitivity Level		TO-220AB	N/A			
		TO-262	MOL 4			
			MSL1			
	Machine Madel	Class M4 (+/- 700V) <sup>†</sup>				
	Machine Model		AEC-Q101-002			
FOD	Lluman Dady Madal	Class H1C (+/-1500V) <sup>†</sup>				
ESD	Human Body Model	AEC-Q101-001				
	Charged Davise Medal	Class C5 (+/-2000V) <sup>†</sup>				
	Charged Device Model		AEC-Q101-005			
RoHS Cor	RoHS Compliant Yes		Yes			

<sup>†</sup> Highest passing voltage.

## **Revision History**

Date	Comments
11/6//2015	<ul> <li>Updated datasheet with corporate template</li> <li>Corrected ordering table on page 1.</li> </ul>
9/18/2017	Corrected typo error on part marking on page 9,10,11.

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